Se	arcn Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/911,784	YOSHIYAMA ET AL.	
Examiner	Art Unit	
Khanh B. Pham	2167	

	SEARCHED			
Class	Subclass	Date	Examiner	
UPDATE	ALL	6/28/2005	KP	
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	RCH NOTES SEARCH STRA	TEGY)	
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